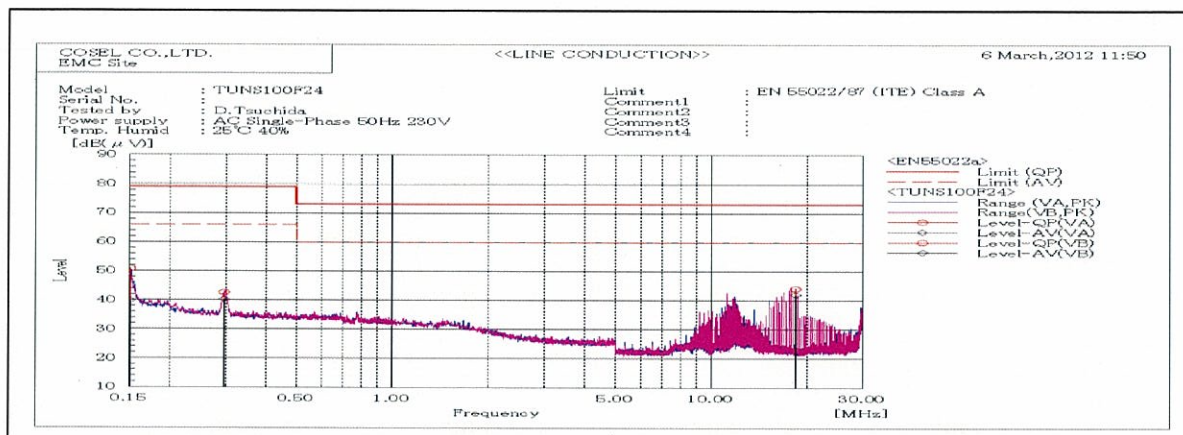
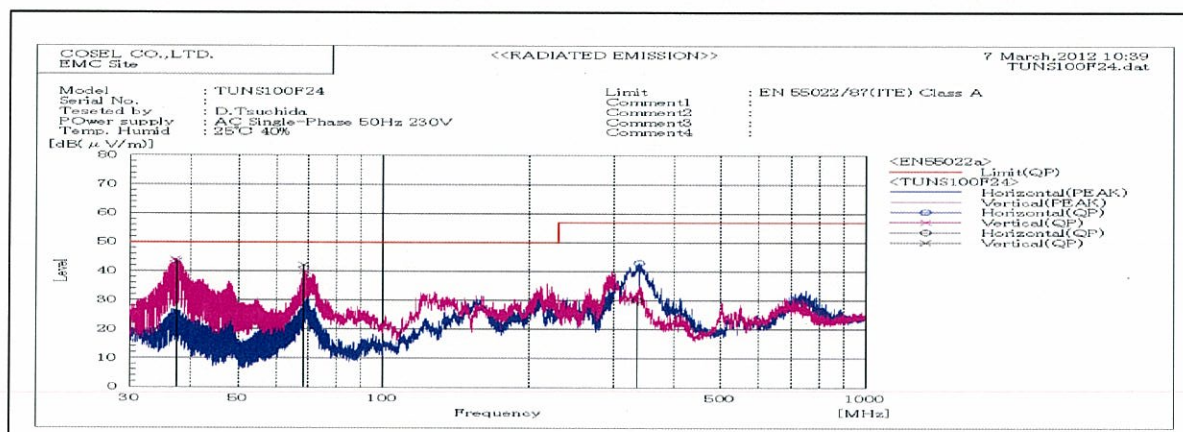


DATA SHEET			Date	18-Apr-12
Model	TUNS100F24		Temp.	25 degreeC
Test	EMI		Humid.	40 %RH
	Line conduction & Radiated emission		Tested by	D.Tsuchida



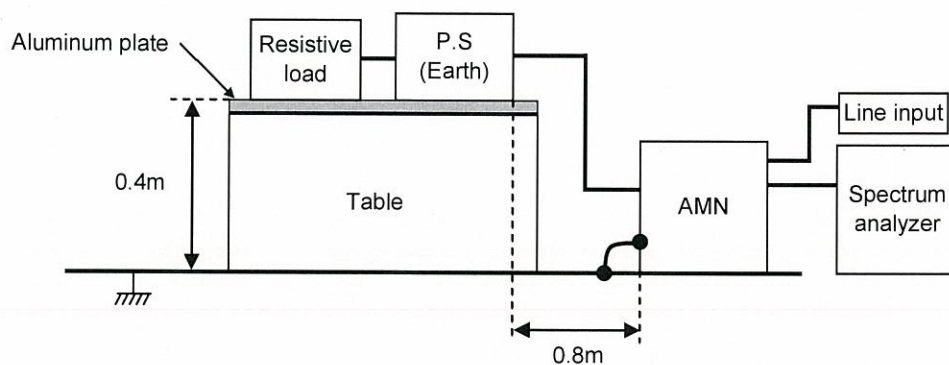
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.15069	VA	40.6	29.6	10.2	50.8	39.8	79	66	28.2	26.2	Pass
0.29509	VB	32.7	30.3	10	42.7	40.3	79	66	36.3	25.7	Pass
18.411	VB	33.4	31.3	10.8	44.2	42.1	73	60	28.8	17.9	Pass



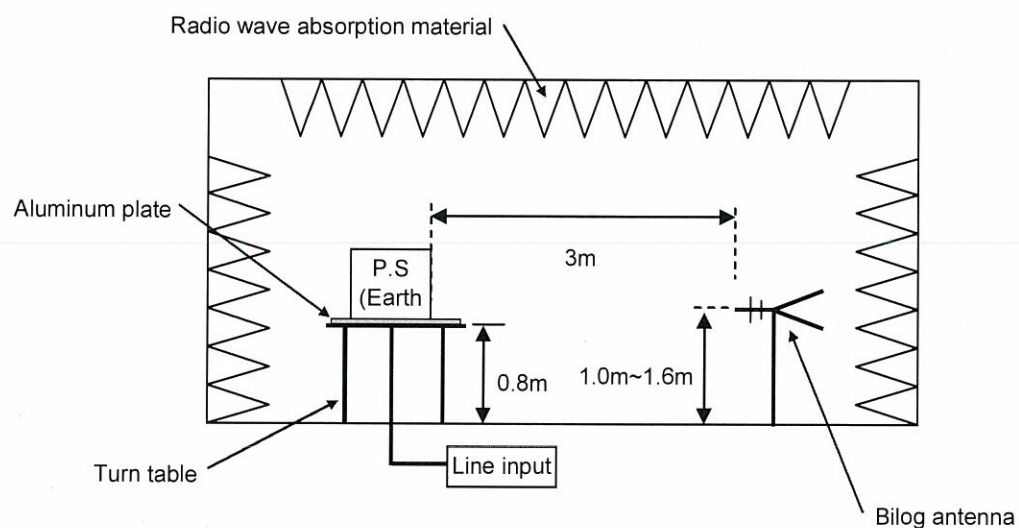
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Height cm	Angle deg	Pass/ Fail
			QP		QP	QP	QP			
37.368	V	Stable	58.7	-15.3	43.4	50	6.6	102	105	Pass
68.505	V	Stable	62.8	-20.6	42.2	50	7.8	113	96	Pass
335.336	H	Stable	45.8	-15.7	30.1	57	26.9	102	4	Pass

DATA SHEET		Date	18-Apr-12
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida

1. Line conduction



2. Radiated emission

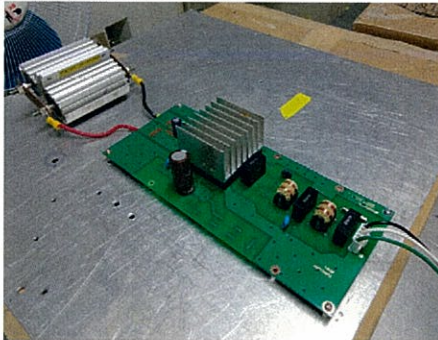


Test: EMI

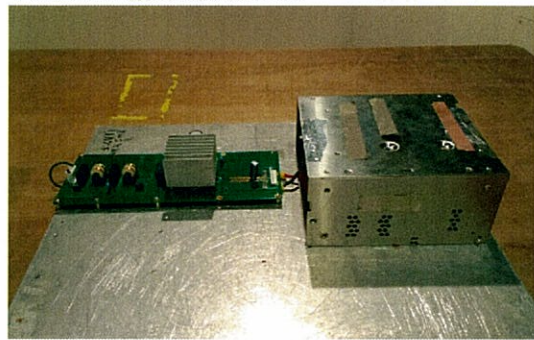
Model Name: TUNS100F Series

○ Photographs of Test Set-Up

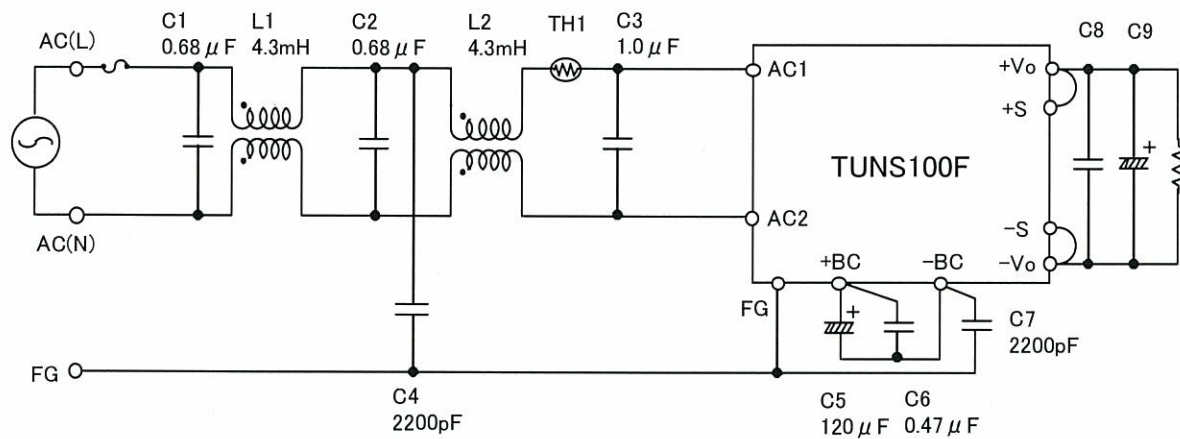
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2 : SSB11V-R17043(NEC TOKIN)

TH1 : 8D2-11(SEMITEC)

C8 : TUNS100F05 10 μF

TUNS100F12 10 μF

TUNS100F24 4.7 μF

C9 : TUNS100F05 2200 μF

TUNS100F12 470 μF

TUNS100F24 220 μF